

<b>Search Notes</b> 				<b>Application/Control No.</b> 09/912,721 <b>Examiner</b> JOHN J. LEE	<b>Applicant(s)/Patent under Reexamination</b> CHEN ET AL. <b>Art Unit</b> 2618		
<b>SEARCHED</b>				<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>			
Class	Subclass	Date	Examiner			DATE	EXMR
455	453,423 446,560 418,420 424,507	6/1/2009	J.L	EAST		6/1/2009	J.L
455	561,67.11	6/1/2009	J.L	Soon Hyun (370)		6/1/2009	J.L
455	509,452.1	6/1/2009	J.L				
455	514,515	6/1/2009	J.L				
370	335,336	6/1/2009	J.L				
375	142,144	6/1/2009	J.L				
<b>INTERFERENCE SEARCHED</b>							
Class	Subclass	Date	Examiner				
455	453,423	6/5/2009	J.L				
455	446,560	6/5/2009	J.L				
455	418,507	6/5/2009	J.L				
Interference and Inventor search		6/5/2009	J.L				